

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/544,054	YONA ET AL.	
Examiner		Art Unit		Page 1 of 1
Christopher E. Lee		2181		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,734,656	03-1998	Prince et al.	370/362
KEM	B	US-5,838,681	11-1998	Bonomi et al.	710/116
6/5/06	C	US-6,016,528	01-2000	Jaramillo et al.	710/107
	D	US-2001/0043700 A1 11/2001	03-1999	SHIMA et al.	379/399.01
	E	US-6,400,819 B1	06-2002	Nakano et al.	379/229
	F	US-5,771,358	06-1998	LaBerge, Paul A.	710/107
	G	US-6,219,706 B1	04-2001	Fan et al.	709/225
	H	US-5,768,270	06-1998	Ha-Duong, Tuan	370/388
	I	US-5,875,351	02-1999	Riley, Dwight D.	710/22
	J	US-5,467,348	11-1995	Fujii et al.	370/399
	K	US-6,047,288	04-2000	Kurosawa et al.	707/10
	L	US-5,452,330	09-1995	Goldstein, Fred R.	370/395.1
	M	US-5,901,332	05-1999	Gephardt et al.	710/116

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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